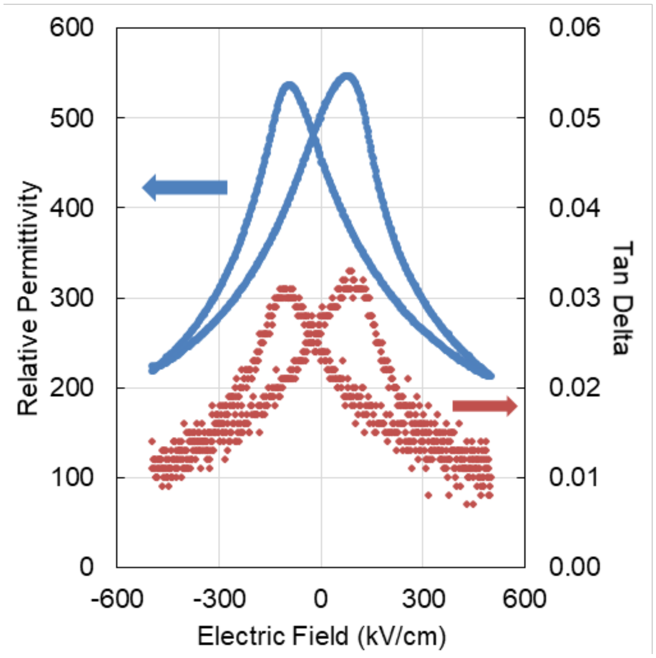

Figure 1: Dielectric constant-electric field loops taken from a metal-insulator-metal capacitor with 200 nm-thick $PbZr_{22}Ti_{78}O_3$ grown by ALD.

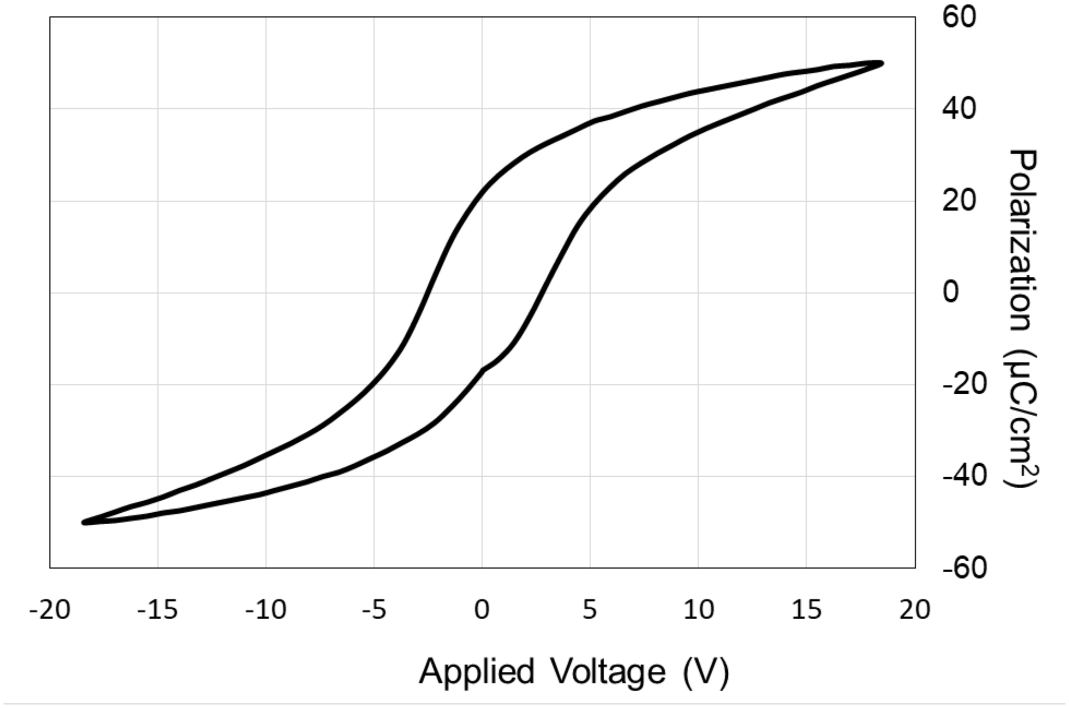

Figure 2: Metal-insulator-metal polarization versus electric field loops for 200 nm-thick ALD $PbZr_{22}Ti_{78}O_3$.